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FQA5N90_F109 900V N-Channel MOSFET

Features

- 5.8A, 900V, $R_{DS(on)}$ = 2.3 Ω @V_{GS} = 10 V Low gate charge (typical 31 nC)
- Low Crss (typical 13pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- RoHS compliant

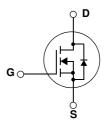


Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power supplies, active power factor correction, electronic lamp ballast based on half bridge topology.





Absolute Maximum Ratings

Symbol	Parameter		FQA5N90_F109	Units	
V _{DSS}	Drain-Source Voltage		900	V	
I _D	Drain Current - Continuous (T _C = 25°C)		5.8	Α	
	- Continuous (T _C = 100°C)		3.67	Α	
I _{DM}	Drain Current - Pulsed	(Note 1)	23.2	Α	
V _{GSS}	Gate-Source Voltage		± 30	V	
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		660	mJ	
I _{AR}	Avalanche Current (Note		5.8	Α	
E _{AR}	Repetitive Avalanche Energy (Note 1)		18.5	mJ	
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.0	V/ns	
P_{D}	Power Dissipation (T _C = 25°C)		185	W	
	- Derate above 25°C		1.47	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range	-55 to +150	°C		
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.68	°C/W	
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.24		°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		40	°C/W	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQA5N90	FQA5N90_F109	TO-3PN			30

Electrical Characteristics T_C = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Charac	teristics	1	-11			W.
BV _{DSS}	Drain-Source Breakdown Voltage	V_{GS} = 0 V, I_{D} = 250 μ A	900			V
$\Delta BV_{DSS}/$ ΔT_J	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		1.0		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 900 V, V _{GS} = 0 V			10	μА
		V _{DS} = 720 V, T _C = 125°C			100	μА
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
On Charact	eristics		•			
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3.0		5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 2.9 A		1.8	2.3	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 50 V, I _D = 2.9 A (Note 4)		5.9		S
Dynamic Cl	haracteristics		1			
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V,		1200	1550	pF
C _{oss}	Output Capacitance	f = 1.0 MHz		110	145	pF
C _{rss}	Reverse Transfer Capacitance			13	17	pF
Switching C	Characteristics					
t _{d(on)}	Turn-On Delay Time	V _{DD} = 450 V, I _D = 5.4A,		28	65	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		65	140	ns
t _{d(off)}	Turn-Off Delay Time	-		65	140	ns
t _f	Turn-Off Fall Time	- (Note 4, 5)		50	110	ns
Qg	Total Gate Charge	V _{DS} = 720 V, I _D = 5.4A,		31	40	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		7.2		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)		15		nC
Drain-Source	ce Diode Characteristics and Maximum Ratings			1	I.	1
I _S	Maximum Continuous Drain-Source Diode Fo	rward Current			5.8	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				23.2	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S =5.8 A			1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 5.4 A,		610		ns
Q _{rr}	Reverse Recovery Charge	$dI_F/dt = 100 \text{ A/}\mu\text{s}$ (Note 4)		5.26		μС

NOTES:

- 1. Repetitive Rating : Pulse width limited by maximum junction temperature
- 2. L = 37mH, I $_{AS}$ =5.8A, V $_{DD}$ = 50V, R $_{G}$ = 25 Ω , Starting T $_{J}$ = 25°C
- 3. $I_{SD} \le 5.4 A$, di/dt $\le 200 A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting T_J = $25^{\circ}C$
- 4. Pulse Test : Pulse width $\leq 300 \mu s,$ Duty cycle $\leq 2\%$
- 5. Essentially independent of operating temperature

Typical Performance Characteristics

Figure 1. On-Region Characteristics

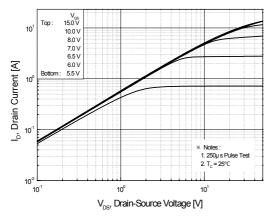


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

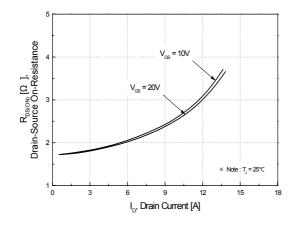


Figure 5. Capacitance Characteristics

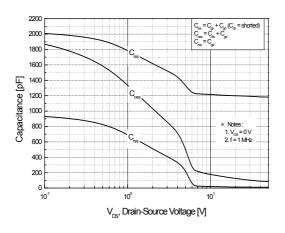


Figure 2. Transfer Characteristics

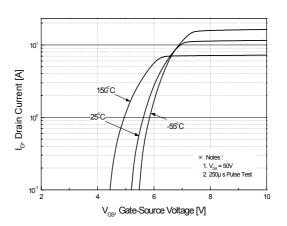


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

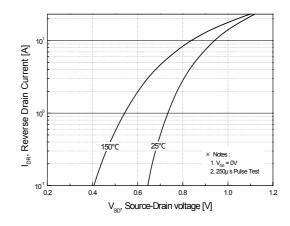
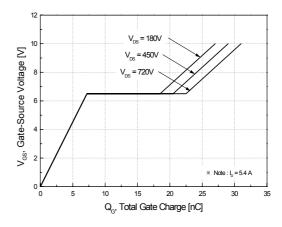


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

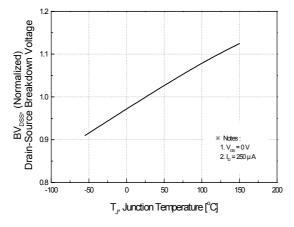


Figure 8. On-Resistance Variation vs. Temperature

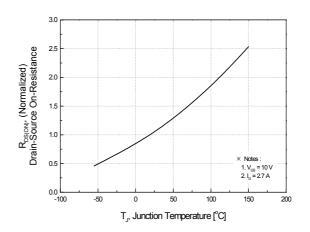
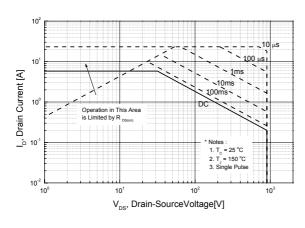


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature



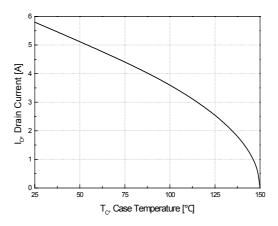
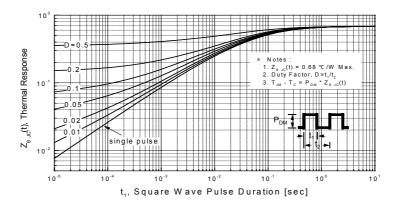
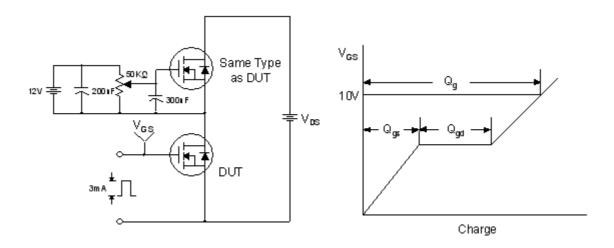


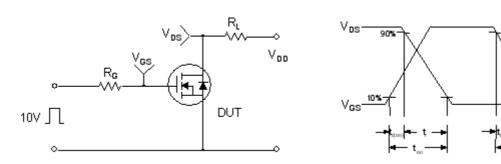
Figure 11. Transient Thermal Response Curve



Gate Charge Test Circuit & Waveform

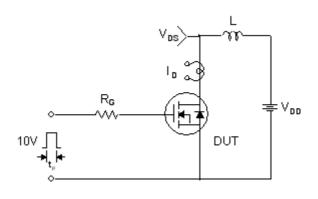


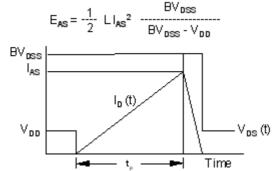
Resistive Switching Test Circuit & Waveforms



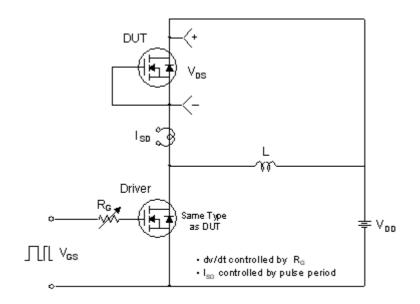
Unclamped Inductive Switching Test Circuit & Waveforms

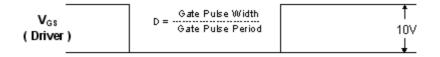
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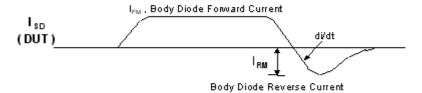


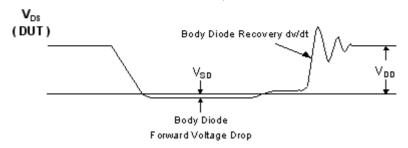


Peak Diode Recovery dv/dt Test Circuit & Waveforms



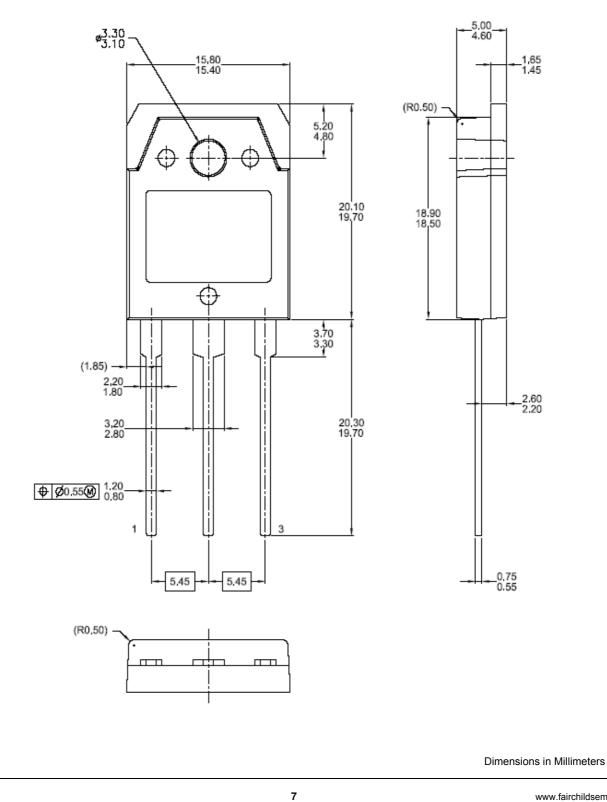






Mechanical Dimensions

TO-3PN







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